

From: Agilent Technologies <event_notification@agilent.com>
Sent: Thursday, March 15, 2012 12:06 PM
To: Hanchett, James (DPH)
Subject: Live event reminder, RFuW and High Speed Digital Seminars on March 27 or 28

View event notification in your browser.

Combining the Power of RF & Microwave with High Speed Digital

Sign up today for Day 1, Day 2, or both days Tuesday, March 27 and Wednesday, March 28 in Chelmsford, MA

Dear Hanchett, Jim Hanchett,
Agilent invites you to join us at the Radisson Hotel & Suites in Chelmsford, MA for this exciting seminar.
Please review the agenda for each day and register for Day 1, Day 2 or both days.

What the seminar is about

In digital standards, every generational change puts new risks in your path. We see it firsthand when creating our products and working with engineers like you. Join us on Day 1 of this complimentary seminar as our industry experts share their knowledge with you in the following applications: DDR, USB, PCIe and Signal Integrity. We can help enhance your ability to create products you'll be proud of.

What is also becoming more prevalent at these high speeds is the increased need to understand the effects of RF on accelerating your device design to market. Day 2 of this seminar will focus on the basic concepts of network analysis, signal analysis and EMI measurements to help you more effectively troubleshoot and diagnose problems with your designs. This event also offers an excellent opportunity for any engineer new to RF to learn the basics of RF and Microwave measurements.

Work with Agilent - and realize your best design.

Presentations

The future of memory technology
Memory technology has really hit a wall because of physics limitations. Understand what these limitations mean for your designs and the tools you use to test them.

Understand USB superspeed and common pitfalls
Find and fix the most common problems engineers face when working on superspeed USB designs and solutions to avoid them including Tx, Rx, and the most advanced triggering system on the market to ensure you are measuring your DUT and not the instruments taking the measurements

PCIe standard updates and 3.0 testing challenges
Understand how the PCI-SIG establishes the new standards and the specific challenges with the recently published 3.0 standard. This will include Tx, Rx, and probing hints for the novice and guru alike.

Signal Integrity Tools for Characterizing High Speed Interconnect
Today's data rates continue beyond the 10 gigabit per second threshold and design engineers require the proper test and measurement tools to design, characterize and show compliance to the highest level of performance. Agilent has two compelling tools for accomplishing important tasks in the design flow of these channels: Physical Layer Test System (PLTS) and ENA Option TDR.

Fundamentals of Network Analysis
Learn the principles of measuring high-frequency electrical networks with network analyzers and how the characterization of linear and nonlinear device behavior can be done.

Fundamentals of Signal Analysis
Learn why spectrum analysis is important for a variety of applications and how to measure system and device performance using a spectrum analyzer.

Electromagnetic Compatibility and Product Development
The integration of an electromagnetic compatibility strategy into the product development cycle is extremely important in today's shortened time lines.

Register for this event today. Seating is limited, so please register early.

Attend the complimentary seminar

Day 1 - Tuesday, March 27, 2012
High Speed Digital
8:00 AM - 11:30 AM: Continental breakfast and lunch will be provided

Day 2 - Wednesday, March 28, 2012
RF Back to Basics
8:00 AM - 11:30 AM: Continental breakfast and lunch will be provided

Radisson Hotel & Suites
Chelmsford, MA
10 Independence Dr., Chelmsford, MA 01824

register now for Day 1, Day 2, or Both days

Agenda for Day 1

8:00 AM - 8:30 AM: Registration and continental breakfast

8:30 AM - 10:00 AM: The future of memory technology

10:00 AM - 10:30 AM: Coffee break

10:30 AM - 12:00 PM: Understand USB SuperSpeed and common pitfalls

12:00 PM - 1:00 PM: Complimentary lunch will be provided

1:00 PM - 2:30 PM: PCIe standard updates and 3.0 testing challenges

2:30 PM - 2:45 PM: Break

2:45 PM - 4:15 PM: Signal Integrity Tools for Characterizing High Speed Interconnect

Agenda for Day 2

8:00 AM - 8:30 AM: Registration and continental breakfast

8:30 AM - 10:00 AM: Fundamentals of Network Analysis

10:00 AM - 10:30 AM: Coffee break

10:30 AM - 12:00 PM: Fundamentals of Network Analysis Continued

12:00 PM - 1:00 PM: Complimentary lunch will be provided

1:00 PM - 2:15 PM: Fundamentals of Signal Analysis

2:15 PM - 2:30 PM: Break

2:30 PM - 4:00 PM: Electromagnetic Compatibility and Product Development

For a more detailed description of this seminar,
please visit www.agilent.com/find/agilent-university.

We look forward to seeing you there.

Sincerely,

Jenny Greenstreet
Market Development Manager
Agilent Technologies
[search all upcoming events](#)

1-800-829-4444 (US)
1-877-894-4414 (Canada)
[contact an expert - find a partner](#)

PCIe and PCI-SIG are registered trademarks and/or service marks of PCI-SIG.

This information is presented by Agilent and our authorized partners, based on our understanding of your interest. If you prefer not to receive, you may remove your name from this list by clicking on [please remove my name](#) or simply reply to this message. Your email address on record is: james.hanchett@state.ma.us.

Please add the agilent.com domain to your safe sender's list in your email client. Our privacy statement is available at: www.agilent.com/go/privacy and describes our commitment to you regarding privacy. We welcome any questions about Agilent's privacy program at: privacy_advocate@agilent.com or write to: Privacy Advocate at 5301 Stevens Creek Boulevard - PO Box 58059 MS 1B-CQ - Santa Clara, CA 95052-8059.

© Agilent Technologies, Inc. 2012

